Nuclear Instruments and Methods in Physics Research B45 (1989) 731–743
North-Holland

AUTHOR INDEX

Abel, F., G. Amsel, E. d'Artemare, C. Ortega, J. Siejka and G. Vizkelethy, Use of the $^{16}O(^{3}He, \alpha)^{15}O$ reaction for studying oxygen-containing thin films . . . B45 (1990) 100
Ackermans, P.A.J., G.C.R. Krutzen and H.H. Brongersma, The use of a calibration in low-energy ion scattering: preferential sputtering and S segregation in CuPd alloys . . . B45 (1990) 384
Agawa, Y., T. Uchiyama, A. Hoshino, H. Tsuboi, R. Fukui, K. Takagi, H. Yamakawa, T. Matsuo, M. Takai and S. Namba, A 500 keV ion beam accelerator for microbeam formation . . . B45 (1990) 540
Agulló-López, F., see Rebouta, L. . . . B45 (1990) 495
Aizawa, T., see Souda, R. . . . B45 (1990) 364
Aizawa, T., see Souda, R. . . . B45 (1990) 369
Alberts, H.W., see Friedland, E. . . . B45 (1990) 492
Alkemade, P.F.A., see Tong, S.Y. . . . B45 (1990) 30
Alkemade, P.F.A., see Tong, S.Y. . . . B45 (1990) 91
Alkemade, P.F.A., see Mitchell, I.V. . . . B45 (1990) 107
Alkemade, P.F.A., F.H.P.M. Habraken and W.F. Van der Weg, On the ambiguity in the analysis of Rutherford backscattering spectra . . . B45 (1990) 139
Alkemade, P.F.A., see Wong, L. . . . B45 (1990) 637
Alkins, R., see Williams, E.T. . . . B45 (1990) 356
Amoddeo, A., see Jiang, S.L. . . . B45 (1990) 646
Amsel, G., see Vickridge, I. . . . B45 (1990) 6
Amsel, G. and I. Vickridge, Analytic calculation for some useful depth profiles of the linear expansion coefficients used in SPACES . . . B45 (1990) 12
Amsel, G., see Vickridge, I. . . . B45 (1990) 16
Amsel, G., see Abel, F. . . . B45 (1990) 100
Amsel, G., M. Menu, J. Moulin and J. Salomon, The 2 MV tandem Pelletron accelerator of the Louvre museum B45 (1990) 296
Amsel, G., see Menu, M. . . . B45 (1990) 610
Anderson, A.J., see MacArthur, J.D. . . . B45 (1990) 322
Anthony, J.M., see Matteson, S. . . . B45 (1990) 575
Antolak, A.J., see Pontau, A.E. . . . B45 (1990) 503
Aono, M., see Kobayashi, T. . . . B45 (1990) 208
Aono, M., see Katayama, M. . . . B45 (1990) 408
Aono, M., see Kobayashi, T. . . . B45 (1990) 480
Arai, E., see Qiu, Q. . . . B45 (1990) 186
Arai, E., Y. Oguri and M. Ogawa, IBA using a small tandem and a single-ended Van de Graaff . . . B45 (1990) 234
Arrale, A.M., see Matteson, S. . . . B45 (1990) 575
Artemare, E. d', see Abel, F. . . . B45 (1990) 100
Asomoza, R., see Zironi, E.P. . . . B45 (1990) 115
Aune, B., see El Bouanani, M. . . . B45 (1990) 651
Avery, A.J., D.J. Diskett, D.W. Lane, J. Giess and S.J.C. Irvine, The use of helium ion RBS for profiling epitaxial layers of $Cd_xHg_{1-x}Te$ . . . B45 (1990) 181

Bakhru, H., see Benenson, R.E. . . . B45 (1990) 519
Barraud, J.Y., see Barthe, M.F. . . . B45 (1990) 105
Barros Leite, C.V., see Stedile, F.C. . . . B45 (1990) 627
Barthe, M.F., A. Giovagnoli, G. Blondiaux, J.L. Debrun, Y. Tregoat and J.Y. Barraud, Fast analysis of oxygen in fluoride glasses (ZBLAN) by charged-particle activation [$^{16}O(d, n)^{17}F$] . . . B45 (1990) 105
Barthe, M.F., see Gelin, P. . . . B45 (1990) 580
Bauer, P., see Steinbauer, E. . . . B45 (1990) 171
Bauer, P., Stopping power of light ions near the maximum . . . B45 (1990) 673
Baumann, H., see Kuhn, D. . . . B45 (1990) 252
Baumann, S.M., C.C. Martner, D.W. Martin, R.J. Blattner and A.J. Braundmeier Jr, A study of electron beam evaporated SiO_2, TiO_2, and Al_2O_3 films using RBS, HFS, and SIMS . . . B45 (1990) 664
Baumvol, I.J.R., see Stedile, F.C. . . . B45 (1990) 627
Bech Nielsen, B., see Smulders, P.J.M. . . . B45 (1990) 438

0168-583X/90/$03.50 © Elsevier Science Publishers B.V.
(North-Holland)

Behar, M., see Grande, P.L. . . . B45 (1990) 689
Bélanger, P., see Houdayer, A.J. . . . B45 (1990) 632
Belhadfa, A., see Hinrichsen, P.F. . . . B45 (1990) 532
Benenson, R.E., Analysis of proton channeling by lead fluoride . . . B45 (1990) 499
Benenson, R.E., P. Berning and H. Bakhru, Ion-beam mixing in micro-size widths . . . B45 (1990) 519
Benmansour, M., see Fallavier, M. . . . B45 (1990) 130
Bentourkia, M., see Gujrathi, S.C. . . . B45 (1990) 260
Bernas, H., see Cottereau, E. . . . B45 (1990) 293
Berning, P., see Benenson, R.E. . . . B45 (1990) 519
Bertrand, P., see Pierson, E. . . . B45 (1990) 374
Beuken, J.-M., see Pierson, E. . . . B45 (1990) 374
Biersack, J., see Steinbauer, E. . . . B45 (1990) 171
Biersack, J.P., see Grande, P.L. . . . B45 (1990) 689
Bird, J.R., Total analysis by IBA . . . B45 (1990) 516
Blattner, R.J., see Baumann, S.M. . . . B45 (1990) 664
Blondiaux, G., see Barthe, M.F. . . . B45 (1990) 105
Bodart, F., see Terwagne, G. . . . B45 (1990) 95
Boerma, D.O., see Smulders, P.J.M. . . . B45 (1990) 438
Boerma, D.O., see Smulders, P.J.M. . . . B45 (1990) 450
Boni, C., A. Caridi, E. Cereda and G.M. Braga Marcazzan, PIXE–PIGE analysis of thin fly-ash samples . . . B45 (1990) 352
Braga Marcazzan, G.M., see Boni, C. . . . B45 (1990) 352
Braundmeier Jr, A.J., see Baumann, S.M. . . . B45 (1990) 664
Bräunig, D., see Briere, M.A. . . . B45 (1990) 45
Brice, D.K. and B.L. Doyle, A curved detection slit to improve ERD energy and depth resolution . . . B45 (1990) 265
Briere, M.A., F. Wulf and D. Bräunig, Measurements of the accumulation of hydrogen at the silicon–silicon-dioxide interface using nuclear reaction analysis . . . B45 (1990) 45
Brissaud, I., see Houdayer, A.J. . . . B45 (1990) 632
Brongersma, H.H., see Ackermans, P.A.J. . . . B45 (1990) 384
Brongersma, H.H., see Van Leerdam, G.C. . . . B45 (1990) 390
Brongersma, H.H., see Scanlon, P.J. . . . B45 (1990) 615
Browning, J.S., Single-event correlation between heavy ions and ^{252}Cf fission fragments . . . B45 (1990) 714
Bruley, J., P. Madakson and J.C. Liu, Characterization of CVD-hydrogenated diamondlike thin films on silicon by EELS, RBS/channeling and nuclear reaction analysis . . . B45 (1990) 618
Bruynseraede, Y., see Wu, M.F. . . . B45 (1990) 658
Bultena, S., see Oxorn, K. . . . B45 (1990) 166
Bushby, S.J., see Mitchell, I.V. . . . B45 (1990) 107
Butler, J.W., Criteria for validity of Rutherford scatter analyses . . . B45 (1990) 160

Calcagno, L., S. Coffa, C. Spinella and E. Rimini, Ion channeling analysis of extended-defect annealing in silicon by rapid thermal processes . . . B45 (1990) 442
Calligaro, T., see Menu, M. . . . B45 (1990) 610
Campbell, J.L., see Hinrichsen, P.F. . . . B45 (1990) 532
Camplan, J., see Cottereau, E. . . . B45 (1990) 293
Caridi, A., see Boni, C. . . . B45 (1990) 352
Carolissen, R., see Pillay, A.E. . . . B45 (1990) 333
Cereda, E., see Boni, C. . . . B45 (1990) 352
Chang, C.S., see Cornelison, D.M. . . . B45 (1990) 394
Chater, R.J., J.A. Kilner, K.J. Reeson, A.K. Robinson and P.L.F. Hemment, ^{18}O isotope studies on the redistribution of oxygen in noncontinuous buried layers formed by high-dose oxygen ion implantation . . . B45 (1990) 110
Chaumont, J., see Cottereau, E. . . . B45 (1990) 293
Chayahara, A., see Kinomura, A. . . . B45 (1990) 523
Chayahara, A., see Kinomura, A. . . . B45 (1990) 536
Cheng Huan-Sheng, Chui Zhi-Xiang, Xu Hong-Jie, Yao Xiao-Wei and Yang Fu-Jia, Studies of surface atomic structure of Al(100) by MeV ion scattering . . . B45 (1990) 424
Cheng Huansheng, see Wu Shiming . . . B45 (1990) 227
Cherniak, D.J., W.A. Lanford and F.J. Ryerson, The use of ion beam techniques to characterize lead diffusion in minerals . . . B45 (1990) 230
Chevarier, A., see El Bouanani, M. . . . B45 (1990) 651
Chevarier, N., see El Bouanani, M. . . . B45 (1990) 651
Chou, N., see Madakson, P. . . . B45 (1990) 216
Chou, N.J., T.H. Zabel, J. Kim and J.J. Ritsko, Residual carbon detection in ceramic substrates by a nuclear reaction technique . . . B45 (1990) 86

Chu, W.-K., see Parkih, N.R. B45 (1990) 70
Chu, W.-K., see Hofsäss, H.C. B45 (1990) 151
Chu, W.-K., see Liu, B. B45 (1990) 420
Chui Zhi-Xiang, see Cheng Huan-Sheng B45 (1990) 424
Clark, A.H., see MacArthur, J.D. B45 (1990) 322
Cliche, L., see Oxorn, K. B45 (1990) 166
Cliche, L., S.C. Gujrathi and L.A. Hamel, Pulse height defects for ^{16}O, ^{35}Cl and ^{81}Br ions in silicon surface barrier detectors B45 (1990) 270
Cliche, L., see Hinrichsen, P.F. B45 (1990) 275
Coffa, S., see Calcagno, L. B45 (1990) 442
Conrad, J.R., see Han, S.H. B45 (1990) 701
Cornelison, D.M., C.S. Chang and I.S.T. Tsong, Impact-collision ion-scattering spectrometry studies of the Si(111)–($\sqrt{3} \times \sqrt{3}$)In surface B45 (1990) 394
Cottereau, E., J. Camplan, J. Chaumont, R. Meunier and H. Bernas, ARAMIS: an ambidextrous 2 MV accelerator for IBA and MeV implantation B45 (1990) 293
Cousens, D.R., see Sie, S.H. B45 (1990) 543
Cousons, D.R., see Sie, S.H. B45 (1990) 604
Craig, R., see Williams, E.T. B45 (1990) 356
Crawford, J.E., see Houdayer, A.J. B45 (1990) 632
Crine, J.P., see Hinrichsen, P.F. B45 (1990) 532

Da Silva, M.F., see Rebouta, L. B45 (1990) 495
Daley, R.S. and R.S. Williams, Impact-collision ion scattering spectroscopy for direct surface structure analysis . B45 (1990) 380
D'Artemare, E., see Abel, F. B45 (1990) 100
Daudin, B., M. Dubus and F. Viargues, Description of a sample holder for ion channeling near liquid-helium temperature B45 (1990) 290
Dautet, H., see Houdayer, A.J. B45 (1990) 632
Davis, C., see Williams, E.T. B45 (1990) 356
De Folter, L.C., see Mutsaers, P.H.A. B45 (1990) 557
De Voigt, M.J.A., see Mutsaers, P.H.A. B45 (1990) 557
Debrun, J.L., see Barthe, M.F. B45 (1990) 105
Debrun, J.L., see Gelin, P. B45 (1990) 580
Deckers, S., F.H.P.M. Habraken, W.F. Van der Weg, A.W. Denier van der Gon, B. Pluis and J.F. Van der Veen, Segregation at the clean and oxidized $Pt_{0.5}Ni_{0.5}(111)$ surface studied by medium-energy ion scattering B45 (1990) 416
Del Carmine, P., see MacArthur, J.D. B45 (1990) 315
Del Carmine, P., F. Lucarelli, P.A. Mandò, G. Moscheni, A. Pecchioli and J.D. MacArthur, PIXE measurements of air particulate elemental composition in the urban area of Florence, Italy B45 (1990) 341
Della Mea, G., see Matzke, Hj. B45 (1990) 194
Denier van der Gon, A.W., see Deckers, S. B45 (1990) 416
Denier van der Gon, A.W., see Smith, R.J. B45 (1990) 429
Dicello, J.F., M.E. Schillaci and L.-C. Liu, Cross sections for pion, proton, and heavy-ion production from 800 MeV protons incident upon aluminum and silicon B45 (1990) 135
Dicello, J.F., J.T. Lyman, J.C. McDonald and L.J. Verhey, A portable system for microdosimetric intercomparisons by task group #20 of the American Association of Physicists in Medicine (AAPM) B45 (1990) 724
Diéguez, E., see Rebouta, L. B45 (1990) 495
Dignard-Bailey, L., see Jackman, J.A. B45 (1990) 592
Diskett, D.J., see Avery, A.J. B45 (1990) 181
Donahue, D.J., A.J.T. Jull and T.W. Linick, Some archaeologic applications of accelerator radiocarbon analysis B45 (1990) 561
Downing, R.G., see Parkih, N.R. B45 (1990) 70
Doyle, B.L., see Walsh, D.S. B45 (1990) 62
Doyle, B.L., see Knapp, J.A. B45 (1990) 143
Doyle, B.L., see Brice, D.K. B45 (1990) 265
Doyle, B.L., see Lee, S.R. B45 (1990) 285
Dubreuil, B., see Gelin, P. B45 (1990) 580
Dubus, M., see Daudin, B. B45 (1990) 290
Duggan, J.L., see Matteson, S. B45 (1990) 575
Durocher, J.J.G., see McKee, J.S.C. B45 (1990) 513

El Bouanani, M., A. Chevarier, N. Chevarier, E. Gerlic, N. Moncoffre, M. Stern, J.C. Magne and B. Aune, Ion bombardment effect on a Nb/Cu interface studied by RBS, NRS, SEM techniques B45 (1990) 651

Fallavier, M., M. Benmansour and J.P. Thomas, IBA applied to adsorption and coadsorption studies of H_2 and C_6H_6 on Ni(111) ... B45 (1990) 130
Fathauer, R.W., see Hashimoto, S. ... B45 (1990) 434
Feldman, L.C., see Savin, W. ... B45 (1990) 417
Fenter, P., see Gustafsson, T. ... B45 (1990) 398
Fleming, S.J., see Swann, C.P. ... B45 (1990) 311
Fletcher, M., see Friedland, E. ... B45 (1990) 492
Forster, J.S., J.R. Leslie and T. Laursen, Scattering recoil coincidence spectrometry: a new experimental technique for profiling hydrogen isotopes in low-Z thin films ... B45 (1990) 176
Freire Jr, F.L., see Matzke, Hj. ... B45 (1990) 194
Freire Jr, F.L., see Stedile, F.C. ... B45 (1990) 627
Frey, E.C., see Parkih, N.R. ... B45 (1990) 70
Friedland, E., H.W. Alberts and M. Fletcher, Temperature dependence of damage ranges in some metals after argon implantation ... B45 (1990) 492
Frontier, J.P., see Tirira, J. ... B45 (1990) 147
Frontier, J.P., see Tirira, J. ... B45 (1990) 203
Fujihana, T., Y. Okabe, K. Takahashi and M. Iwaki, RBS, AES and XRD investigations of high-dose nitrogen-implanted Ti, Cr, Fe, Zr and Nb sheets ... B45 (1990) 669
Fujimoto, F., A study of hydrogen atoms on solid surfaces by utilizing the Doppler broadening of the $^1H(^{15}N, \alpha\gamma)^{12}C$ nuclear reaction ... B45 (1990) 49
Fujimoto, F., see Tanaka, M. ... B45 (1990) 223
Fukui, R., see Agawa, Y. ... B45 (1990) 540

Gagnon, G., see Houdayer, A.J. ... B45 (1990) 632
Galligan, E., see Madakson, P. ... B45 (1990) 216
Gallop, D., see McKee, J.S.C. ... B45 (1990) 513
Gärtner, K., see Wesch, W. ... B45 (1990) 446
Gaskin, I., see Williams, E.T. ... B45 (1990) 356
Geerk, J., see Meyer, O. ... B45 (1990) 483
Gelin, P., M.F. Barthe, J.L. Debrun, O. Gobert, T. Gibert, R.L. Inglebert and B. Dubreuil, Analysis of carbon at trace level by ion sputtering and laser resonant postionization ... B45 (1990) 580
Gerlic, E., see El Bouanani, M. ... B45 (1990) 651
Gibert, T., see Gelin, P. ... B45 (1990) 580
Gibson, W.M., see Hashimoto, S. ... B45 (1990) 434
Gibson, W.M., see Xiao, Q.F. ... B45 (1990) 464
Gibson, W.M., see Luo, L. ... B45 (1990) 488
Giess, J., see Avery, A.J. ... B45 (1990) 181
Giovagnoli, A., see Barthe, M.F. ... B45 (1990) 105
Gobert, O., see Gelin, P. ... B45 (1990) 580
Gordon, B.M., A.L. Hanson, K.W. Jones, J.G. Pounds, M.L. Rivers, G. Schidlovsky, P. Spanne and S.R. Sutton, The application of synchrotron radiation to microprobe trace-element analysis of biological samples ... B45 (1990) 527
Götz, G., see Wesch, W. ... B45 (1990) 446
Grande, P.L., M. Behar, J.P. Biersack and F.C. Zawislak, Range parameters of heavy ions implanted into Be films ... B45 (1990) 689
Griffin, W.L., see Sie, S.H. ... B45 (1990) 604
Griffiths, K., see Mitchell, I.V. ... B45 (1990) 107
Grime, G., see Reeson, K.J. ... B45 (1990) 327
Grime, G.W., F. Watt and D.N. Jamieson, The influence of accelerator parameters on the performance of submicron quadrupole probe-forming systems ... B45 (1990) 508
Gujrathi, S.C., see Oxorn, K. ... B45 (1990) 166
Gujrathi, S.C., D.W. Hetherington, P.F. Hinrichsen and M. Bentourkia, The detection of heavy ions with PIN diodes ... B45 (1990) 260
Gujrathi, S.C., see Cliche, L. ... B45 (1990) 270
Gujrathi, S.C., see Hinrichsen, P.F. ... B45 (1990) 275
Günzler, R., see Oberschachtsiek, P. ... B45 (1990) 20
Guo, X.S., W.A. Lanford and K.P. Rodbell, Ion beam analysis of edge effects in Al/M/Al stripes ... B45 (1990) 123
Guo, X.S., W.A. Lanford and K.P. Rodbell, A 2-dimensional RBS simulation program for studying the edges of multilayer integrated cicuit components ... B45 (1990) 157
Guo, X.S., The wake potential and dynamic screening in a hydrogen system ... B45 (1990) 693
Guo, X.S., Calculation of the stopping power changes due to the superconducting transition in high-T_c $YBa_2Cu_3O_7$ superconductors ... B45 (1990) 698

Gustafsson, T., P. Fenter and P. Häberle, Medium-energy ion scattering studies of the structure of some reconstructed metal surfaces B45 (1990) 398

Haba, M., see Tanaka, M. B45 (1990) 223
Häberle, P., see Gustafsson, T. B45 (1990) 398
Habraken, F.H.P.M., see Alkemade, P.F.A. B45 (1990) 139
Habraken, F.H.P.M., see Deckers, S. B45 (1990) 416
Hajsaleh, J.Y., see Matteson, S. B45 (1990) 575
Halden, N.M., see McKee, J.S.C. B45 (1990) 513
Hamanaka, H., M. Okane and Y. Yamamoto, Improvement of the energy resolution and the S/N ratio of a crystal spectrometer combined with a position-sensitive proportional counter for PIXE B45 (1990) 360
Hamel, L.A., see Cliche, L. B45 (1990) 270
Han, S.H., G.L. Kulcinski and J.R. Conrad, Computer simulation of ion beam mixing B45 (1990) 701
Hanawa, T., see Oura, K. B45 (1990) 199
Hanawa, T., see Nakahara, T. B45 (1990) 467
Hanson, A.L., see Gordon, B.M. B45 (1990) 527
Hashimoto, S., Q.F. Xiao, W.M. Gibson, C.W. Nieh and R.W. Fathauer, Ion channeling study of single-crystal columns of $CoSi_2$ embedded in epitaxial Si on Si(111) grown by MBE B45 (1990) 434
Hashimoto, S., see Xiao, Q.F. B45 (1990) 464
Hashimoto, S., see Luo, L. B45 (1990) 488
Hayashi, S., see Katayama, M. B45 (1990) 408
Hemment, P.L.F., see Chater, R.J. B45 (1990) 110
Hetherington, D.W., see Gujrathi, S.C. B45 (1990) 260
Hetherington, D.W., see Hinrichsen, P.F. B45 (1990) 275
Hinrichsen, P.F., see Gujrathi, S.C. B45 (1990) 260
Hinrichsen, P.F., D.W. Hetherington, S.C. Gujrathi and L. Cliche, Heavy-ion energy resolution of SSB detectors B45 (1990) 275
Hinrichsen, P.F., G. Kajrys, A. Houdayer, A. Jeremie, A. Belhadfa, J.P. Crine and J.L. Campbell, Micro-PIXE analysis of impurity distributions in "trees" grown in high-voltage cables B45 (1990) 532
Hjörvarsson, B. and J. Rydén, Off-resonance and straggling measurements using the $^1H(^{15}N, \alpha\gamma)^{12}C$ reaction . B45 (1990) 36
Hodges, L.S., see Matteson, S. B45 (1990) 575
Hofsäss, H.C., see Parkih, N.R. B45 (1990) 70
Hofsäss, H.C., N.R. Parikh, M.L. Swanson and W.-K. Chu, Depth profiling of light elements using elastic recoil coincidence spectroscopy (ERCS) B45 (1990) 151
Horn, K.M. and W.A. Lanford, Suppression of background radiation in BGO and NaI detectors used in nuclear reaction analysis B45 (1990) 256
Hoshino, A., see Agawa, Y. B45 (1990) 540
Hossain, T.Z., see Parkih, N.R. B45 (1990) 70
Houdayer, A., see Hinrichsen, P.F. B45 (1990) 532
Houdayer, A.J., P. Bélanger, I. Brissaud, J.E. Crawford, H. Dautet, G. Gagnon, J.K.P. Lee, J. Obert, J. Pinard and K. Scholberg, An investigation of laser desorption of Au by PIXE and RBS techniques using a He beam B45 (1990) 632
Hua Zhongyi, see Wu Shiming B45 (1990) 227
Hult, M., see Pallon, J. B45 (1990) 548
Hyltén, G., see Pallon, J. B45 (1990) 548

Inglebert, R.L., see Gelin, P. B45 (1990) 580
Inoue, K., see Takai, M. B45 (1990) 553
Irvine, S.J.C., see Avery, A.J. B45 (1990) 181
Ishibashi, K., see Takai, M. B45 (1990) 553
Ishizawa, Y., see Souda, R. B45 (1990) 364
Ishizawa, Y., see Souda, R. B45 (1990) 369
Itoh, N., see Matsunami, N. B45 (1990) 412
Iwaki, M., see Kobayashi, T. B45 (1990) 208
Iwaki, M., Y. Okabe and K. Yabe, Comparison between oxygen depth profiles in oxygen-implanted titanium measured by RBS and XPS combined with argon sputtering B45 (1990) 212
Iwaki, M., see Kobayashi, T. B45 (1990) 480
Iwaki, M., see Fujihana, T. B45 (1990) 669
Iwata, Y., see Tanaka, M. B45 (1990) 223

Jackman, J.A., L. Dignard-Bailey, R.S. Storey, C. MacPherson, S. Rolfe, L. Van der Zwan and T.E. Jackman, Matrix effects in SIMS depth profiles of SiGe superlattices B45 (1990) 592
Jackman, T.E., see Jackman, J.A. B45 (1990) 592

Jaffrezic, H., see Moncoffre, N. ... B45 (1990) 81
Jamieson, D.N., see Grime, G.W. ... B45 (1990) 508
Jensen, H., see Terwagne, G. ... B45 (1990) 95
Jeremie, A., see Hinrichsen, P.F. ... B45 (1990) 532
Jeynes, C., see Reeson, K.J. ... B45 (1990) 327
Jiang, S.L., A. Oliva, A. Amoddeo and R. Kelly, Composition profiles due to bombardment-induced segregation in Cu–Ni samples as deduced by Auger spectroscopy ... B45 (1990) 646
Johansson, S.A.E., see Pallon, J. ... B45 (1990) 548
Jones, K.W., see Gordon, B.M. ... B45 (1990) 527
Jordanov, A., see Wesch, W. ... B45 (1990) 446
Jull, A.J.T., see Donahue, D.J. ... B45 (1990) 561

Kajrys, G., see Hinrichsen, P.F. ... B45 (1990) 532
Kalbitzer, S., see Oberschachtsiek, P. ... B45 (1990) 20
Kanasaki, J.-I., see Matsunami, N. ... B45 (1990) 412
Katayama, M., E. Nomura, H. Soejima, S. Hayashi and M. Aono, Real-time monitoring of molecular-beam epitaxy processes with coaxial impact-collision ion scattering spectroscopy (CAICISS) ... B45 (1990) 408
Katsanos, A., see Tsartsarakos, C. ... B45 (1990) 33
Kawata, Y., see Takai, M. ... B45 (1990) 553
Kelly, R., see Jiang, S.L. ... B45 (1990) 646
Kemmer, J., Advanced concepts for semiconductor nuclear radiation detectors ... B45 (1990) 247
Kieser, W.E., L.R. Kilius, M.-J. Nadeau, J. Perez and A.E. Litherland, Tandetron accelerators as AMS instruments ... B45 (1990) 570
Kilius, L.R., see Rucklidge, J.C. ... B45 (1990) 565
Kilius, L.R., see Kieser, W.E. ... B45 (1990) 570
Kilner, J.A., see Chater, R.J. ... B45 (1990) 110
Kim, J., see Chou, N.J. ... B45 (1990) 86
Kinomura, A., M. Takai, S. Namba, M. Satou and A. Chayahara, RBS tomography of SOI structures using a MeV ion microprobe ... B45 (1990) 523
Kinomura, A., M. Takai, S. Namba, M. Satou and A. Chayahara, Characterization of masklessly deposited metal lines by a micro-RBS probe ... B45 (1990) 536
Kinomura, A., see Takai, M. ... B45 (1990) 553
Kitoh, K., see Yamamura, Y. ... B45 (1990) 403
Kitoh, K., see Matsunami, N. ... B45 (1990) 412
Klein, S.S., see Mutsaers, P.H.A. ... B45 (1990) 557
Knapp, J.A. and B.L. Doyle, Heavy-ion backscattering spectrometry (HIBS) for high-sensitivity surface impurity detection ... B45 (1990) 143
Knox, J.M., R.J. McLeod, D.R. Mayo and X. Qian, Fits of non-Rutherford cross sections and their inclusion in the RUMP simulator ... B45 (1990) 26
Knox, J.M., see Walsh, D.S. ... B45 (1990) 62
Kobayashi, K., see Tanaka, M. ... B45 (1990) 223
Kobayashi, T., O. Mishima, M. Iwaki, H. Sakairi and M. Aono, Crystallographic polarity of idemorphic faces on a cubic boron nitride single crystal determined by Rutherford backscattering spectroscopy ... B45 (1990) 208
Kobayashi, T., S. Takekawa, K. Shigematsu, T. Takahashi, M. Iwaki, H. Sakairi, H. Takahara and M. Aono, Ion irradiation effect in a Bi–Sr–Ca–Cu–O oxide superconductor ... B45 (1990) 480
Komaki, K., see Tanaka, M. ... B45 (1990) 223
Kristiansson, P., see Pallon, J. ... B45 (1990) 548
Krutzen, G.C.R., see Ackermans, P.A.J. ... B45 (1990) 384
Kuhn, D., F. Rauch and H. Baumann, A low-background detection system using a BGO detector for sensitive hydrogen analysis with the $^{1}H(^{15}N, \alpha\gamma)^{12}C$ reaction ... B45 (1990) 252
Kuiper, A.E.T., see Willemsen, M.F.C. ... B45 (1990) 242
Kulcinski, G.L., see Han, S.H. ... B45 (1990) 701
Kurimoto, K., see Qiu, Q. ... B45 (1990) 186
Kwietniak, M.S., see Wielunski, L.S. ... B45 (1990) 455
Kwietniak, M.S., see Wielunski, L.S. ... B45 (1990) 459

Lane, D.W., see Avery, A.J. ... B45 (1990) 181
Lanford, W.A., see Guo, X.S. ... B45 (1990) 123
Lanford, W.A., see Guo, X.S. ... B45 (1990) 157
Lanford, W.A., see Cherniak, D.J. ... B45 (1990) 230
Lanford, W.A., see Horn, K.M. ... B45 (1990) 256

Langouche, G., see Wu, M.F. B45 (1990) 658
Larsson, P., see Pallon, J. B45 (1990) 548
Laursen, T. and G.K. Wolf, Deuterium distributions in cathodically charged type-304 stainless steel measured by the d(^{3}He, p)α nuclear reaction B45 (1990) 66
Laursen, T., see Forster, J.S. B45 (1990) 176
Leclair, J., see Mertens, P.W. B45 (1990) 586
Lee, J.K.P., see Houdayer, A.J. B45 (1990) 632
Lee, J.W., see Pfandzelter, R. B45 (1990) 641
Lee, S.R., D.S. Walsh and B.L. Doyle, Characterization of external ^{3}He ion beams used for ex-vacuo nuclear reaction analysis of deuterium B45 (1990) 285
Lennard, W.N., see Tong, S.Y. B45 (1990) 30
Lennard, W.N., see Tong, S.Y. B45 (1990) 91
Lennard, W.N., see Mitchell, I.V. B45 (1990) 107
Lennard, W.N., S.Y. Tong, G.R. Massoumi and L. Wong, On the calibration of low-energy ion accelerators ... B45 (1990) 281
Lennard, W.N., see Wong, L. B45 (1990) 637
Lenssen, K.-M.H., see Van Leerdam, G.C. B45 (1990) 390
Leslie, J.R., see Forster, J.S. B45 (1990) 176
Li, Q., see Meyer, O. B45 (1990) 483
Linick, T.W., see Donahue, D.J. B45 (1990) 561
Linker, G., see Meyer, O. B45 (1990) 483
Litherland, A.E., see Kieser, W.E. B45 (1990) 570
Liu, B., G.S. Sandhu, N.R. Parikh, M.L. Swanson and W.-K. Chu, Regrowth of radiation-damaged layers in natural diamond B45 (1990) 420
Liu, J.C., see Bruley, J. B45 (1990) 618
Liu, L.-C., see Dicello, J.F. B45 (1990) 135
Los, G., see Mutsaers, P.H.A. B45 (1990) 557
Lövestam, N.E.G. and E. Swietlicki, PIXE analysis and imaging of papyrus documents B45 (1990) 307
Lövestam, N.E.G., see Pallon, J. B45 (1990) 548
Lucarelli, F., see MacArthur, J.D. B45 (1990) 315
Lucarelli, F., see Del Carmine, P. B45 (1990) 341
Lucas, S., see Terwagne, G. B45 (1990) 95
Luo, L., G.A. Smith, S. Hashimoto and W.M. Gibson, Room-temperature deposition and initial stages of cobalt silicide interface formation on a Si(111) $\sqrt{3} \times \sqrt{3}$ surface B45 (1990) 488
Lyman, J.T., see Dicello, J.F. B45 (1990) 724

Ma, X.-P., see MacArthur, J.D. B45 (1990) 322
MacArthur, J.D., P. Del Carmine, F. Lucarelli and P.A. Mandò, Identification of pigments in some colours on miniatures from the Medieval Age and early Renaissance B45 (1990) 315
MacArthur, J.D., X.-P. Ma, G.R. Palmer, A.J. Anderson and A.H. Clark, Below-surface analysis of inclusions with PIXE and PIGE B45 (1990) 322
MacArthur, J.D., see Palmer, G.R. B45 (1990) 337
MacArthur, J.D., see Del Carmine, P. B45 (1990) 341
MacPherson, C., see Jackman, J.A. B45 (1990) 592
Madakson, P., S. Nunes, E. Galligan, R. McGouey and N. Chou, RBS analysis of Si diffusion in photoresist during silylation B45 (1990) 216
Madakson, P., see Bruley, J. B45 (1990) 618
Maex, K., see Wu, M.F. B45 (1990) 658
Magne, J.C., see El Bouanani, M. B45 (1990) 651
Maldonado, A., see Zironi, E.P. B45 (1990) 115
Malmqvist, K.G., see Pallon, J. B45 (1990) 548
Mandò, P.A., see MacArthur, J.D. B45 (1990) 315
Mandò, P.A., see Del Carmine, P. B45 (1990) 341
Marble, D.K., see Matteson, S. B45 (1990) 575
Martin, D.W., see Baumann, S.M. B45 (1990) 664
Martner, C.C., see Baumann, S.M. B45 (1990) 664
Masahashi, N., see Tanaka, K. B45 (1990) 471
Massoumi, G.R., see Mitchell, I.V. B45 (1990) 107
Massoumi, G.R., see Lennard, W.N. B45 (1990) 281
Mathur, M.S., see McKee, J.S.C. B45 (1990) 513
Matsunami, N., see Yamamura, Y. B45 (1990) 403

Matsunami, N., K. Kitoh, J.-I. Kanasaki and N. Itoh, High-resolution analysis of protons scattered from solid surfaces ... B45 (1990) 412
Matsuo, T., see Agawa, Y. ... B45 (1990) 540
Matsuo, T., see Takai, M. ... B45 (1990) 553
Matteson, S., D.K. Marble, L.S. Hodges, J.Y. Hajsaleh, A.M. Arrale, M.R. McNeir, J.L. Duggan, F.D. McDaniel and J.M. Anthony, Molecular-interference-free accelerator mass spectrometry ... B45 (1990) 575
Matzke, Hj., G. Della Mea, F.L. Freire Jr and V. Rigato, Determination of hydrogen in leached UO_2 and SYNROC ... B45 (1990) 194
Mayo, D.R., see Knox, J.M. ... B45 (1990) 26
McDaniel, F.D., see Matteson, S. ... B45 (1990) 575
McDonald, J.C., see Dicello, J.F. ... B45 (1990) 724
McGouey, R., see Madakson, P. ... B45 (1990) 216
McGovern, P.E., see Swann, C.P. ... B45 (1990) 311
McKee, J.S.C., J.J.G. Durocher, D. Gallop, N.M. Halden, M.S. Mathur, A. Mirzai, G.R. Smith and Y.H. Yeo, Micro- and milli-PIXE analysis at 40 MeV – why, how and when? ... B45 (1990) 513
McLeod, R.J., see Knox, J.M. ... B45 (1990) 26
McNeir, M.R., see Matteson, S. ... B45 (1990) 575
Menu, M., see Walter, P. ... B45 (1990) 119
Menu, M., see Amsel, G. ... B45 (1990) 296
Menu, M., IBA in the museum: why AGLAE ... B45 (1990) 597
Menu, M., T. Calligaro, J. Salomon, G. Amsel and J. Moulin, The dedicated accelerator-based IBA facility AGLAE at the Louvre ... B45 (1990) 610
Menzel, N. and K. Wittmaack, RBS study on bombardment-induced redistribution of copper impurities in silicon using neon, oxygen and nitrogen ion beams at different impact angles ... B45 (1990) 219
Mertens, P.W., W. Vandervorst and J. Leclair, Oxygen redistribution in silicon during zone melting recrystallization ... B45 (1990) 586
Meunier, R., see Cottereau, E. ... B45 (1990) 293
Meyer, O., J. Geerk, Q. Li, G. Linker and X.X. Xi, Epitaxial growth analysis of YBaCuO thin films by ion backscattering and channeling spectrometry ... B45 (1990) 483
Millard, N., see Moncoffre, N. ... B45 (1990) 81
Mirzai, A., see McKee, J.S.C. ... B45 (1990) 513
Misaelides, P., see Tsartsarakos, C. ... B45 (1990) 33
Mishima, O., see Kobayashi, T. ... B45 (1990) 208
Miskin, J., see Oxorn, K. ... B45 (1990) 166
Mitchell, I.V., see Tong, S.Y. ... B45 (1990) 30
Mitchell, I.V., see Tong, S.Y. ... B45 (1990) 91
Mitchell, I.V., G.R. Massoumi, W.N. Lennard, S.Y. Tong, P.F.A. Alkemade, K. Griffiths, S.J. Bushby and P.R. Norton, The determination of absoulte oxygen coverage by nuclear reaction analysis ... B45 (1990) 107
Mitchell, I.V., see Wong, L. ... B45 (1990) 637
Mizuhara, Y., see Tanaka, K. ... B45 (1990) 471
Möller, W., see Scherzer, B.M.U. ... B45 (1990) 54
Moncoffre, N., N. Millard, H. Jaffrezic and J. Tousset, Boron analysis of thin layers using prompt nuclear techniques ... B45 (1990) 81
Moncoffre, N., see El Bouanani, M. ... B45 (1990) 651
Morse, D.H., see Pontau, A.E. ... B45 (1990) 503
Mosca Jr, D.H., see Stedile, F.C. ... B45 (1990) 627
Moscheni, G., see Del Carmine, P. ... B45 (1990) 341
Moulin, J., see Amsel, G. ... B45 (1990) 296
Moulin, J., see Menu, M. ... B45 (1990) 610
Mutsaers, P.H.A., G. Los, S.S. Klein, L.C. De Folter and M.J.A. De Voigt, The microprobe at the Eindhoven University of Technology ... B45 (1990) 557

Nadeau, M.-J., see Kieser, W.E. ... B45 (1990) 570
Nailand, P., see Watterson, J.I.W. ... B45 (1990) 75
Naitoh, M., see Oura, K. ... B45 (1990) 199
Nakahara, T., S. Ohkura, F. Shoji, T. Hanawa and K. Oura, RBS/channeling study on the annealing behavior of Cu thin films on Si(100) and (111) substrates ... B45 (1990) 467
Nakajima, M., see Qiu, Q. ... B45 (1990) 186
Namba, S., see Kinomura, A. ... B45 (1990) 523
Namba, S., see Kinomura, A. ... B45 (1990) 536

Namba, S., see Agawa, Y. B45 (1990) 540
Namba, S., see Takai, M. B45 (1990) 553
Nastasi, M., see Tesmer, J.R. B45 (1990) 476
Neumann, W. and C. Stalder, Thin-layer activation applied to erosive wear B45 (1990) 126
Nieh, C.W., see Hashimoto, S. B45 (1990) 434
Nomura, E., see Katayama, M. B45 (1990) 408
Norton, P.R., see Mitchell, I.V. B45 (1990) 107
Nunes, S., see Madakson, P. B45 (1990) 216

Oberschachtsiek, P., V. Schüle, R. Günzler, M. Weiser and S. Kalbitzer, Deep range profiling by Rutherford backscattering and nuclear reaction analysis B45 (1990) 20
Obert, J., see Houdayer, A.J. B45 (1990) 632
Ogawa, M., see Qiu, Q. B45 (1990) 186
Ogawa, M., see Arai, E. B45 (1990) 234
Oguri, Y., see Arai, E. B45 (1990) 234
Ohkura, S., see Nakahara, T. B45 (1990) 467
Okabe, Y., see Iwaki, M. B45 (1990) 212
Okabe, Y., see Fujihana, T. B45 (1990) 669
Okane, M., see Hamanaka, H. B45 (1990) 360
Oliva, A., see Jiang, S.L. B45 (1990) 646
Ortega, C., see Abel, F. B45 (1990) 100
Ortega, C., J. Siejka and G. Vizkelethy, Characterization of porous silicon by NRA, RBS and channeling B45 (1990) 622
Oshima, C., see Souda, R. B45 (1990) 364
Oshima, C., see Souda, R. B45 (1990) 369
Oura, K., M. Naitoh, F. Shoji, J. Yamane, K. Umezawa and T. Hanawa, Elastic recoil detection analysis of hydrogen adsorbed on solid surfaces B45 (1990) 199
Oura, K., see Nakahara, T. B45 (1990) 467
Oxorn, K., S.C. Gujrathi, S. Bultena, L. Cliche and J. Miskin, An iterative computer analysis package for elastic recoil detection (ERD) experiments B45 (1990) 166

Pain, G.N., see Wielunski, L.S. B45 (1990) 455
Pain, G.N., see Wielunski, L.S. B45 (1990) 459
Pallon, J., S.A.E. Johansson, M. Hult, G. Hyltén, P. Kristiansson, P. Larsson, N.E.G. Lövestam, K.G. Malmqvist, U.A.S. Tapper and K. Themner, Recent advances in the nuclear microprobe at the Lund Institute of Technology B45 (1990) 548
Palmer, G.R., see MacArthur, J.D. B45 (1990) 322
Palmer, G.R., J.D. MacArthur and M.A. Singer, PIXE and PIGE studies of ion diffusion through phospholipid bilayers containing cholesterol B45 (1990) 337
Parikh, N.R., see Hofsäss, H.C. B45 (1990) 151
Parikh, N.R., see Liu, B. B45 (1990) 420
Parkih, N.R., E.C. Frey, H.C. Hofsäss, M.L. Swanson, R.G. Downing, T.Z. Hossain and W.-K. Chu, Neutron depth profiling by coincidence spectrometry B45 (1990) 70
Pattyn, H., see Wu, M.F. B45 (1990) 658
Pearton, S.J., see Xiao, Q.F. B45 (1990) 464
Pecchioli, A., see Del Carmine, P. B45 (1990) 341
Peisach, M., see Pillay, A.E. B45 (1990) 333
Perez, J., see Kieser, W.E. B45 (1990) 570
Pfandzelter, R. and J.W. Lee, Surface analysis by spectroscopy of Auger electrons induced by fast protons at grazing incidence B45 (1990) 641
Pierson, E., J.-M. Beuken and P. Bertrand, Computer simulation of reionization in ISS B45 (1990) 374
Pillay, A.E., see Watterson, J.I.W. B45 (1990) 75
Pillay, A.E., M. Peisach, R. Carolissen and C.A. Pineda, PIXE determination of silicon/aluminium ratios in zeolites and geological materials B45 (1990) 333
Pinard, J., see Houdayer, A.J. B45 (1990) 632
Pineda, C.A., see Pillay, A.E. B45 (1990) 333
Pluis, B., see Deckers, S. B45 (1990) 416
Pontau, A.E., A.J. Antolak and D.H. Morse, Some practical consideratons for ion microtomography B45 (1990) 503
Pounds, J.G., see Gordon, B.M. B45 (1990) 527

Qian, X., see Knox, J.M. B45 (1990) 26
Qiu, Q., K. Kurimoto, M. Nakajima, M. Ogawa and E. Arai, ERDA of hydrogen and helium using an 8 MeV ^{16}O beam B45 (1990) 186

Rauch, F., see Kuhn, D. ... B45 (1990) 252
Rebouta, L., J.C. Soares, M.F. Da Silva, J.A. Sanz-Garcia, E. Diéguez and F. Agulló-López, Combined RBS/channeling and PAC studies of hafnium-doped $LiNbO_3$ ... B45 (1990) 495
Reeson, K.J., see Chater, R.J. ... B45 (1990) 110
Reeson, K.J., C.J. Stanley, C. Jeynes, G. Grime and F. Watt, PIXE analysis to determine the trace-element concentrations in a series of galena (PbS) specimens from different localities ... B45 (1990) 327
Reid, I., L.E. Seiberling and H.A. Van Rinsvelt, PIXE analysis of GaAs and ZnSe ... B45 (1990) 347
Rickards, J., see Zironi, E.P. ... B45 (1990) 115
Ridgway, M.C., see Scanlon, P.J. ... B45 (1990) 615
Rigato, V., see Matzke, Hj. ... B45 (1990) 194
Rimini, E., see Calcagno, L. ... B45 (1990) 442
Ritsko, J.J., see Chou, N.J. ... B45 (1990) 86
Rivers, M.L., see Gordon, B.M. ... B45 (1990) 527
Robinson, A.K., see Chater, R.J. ... B45 (1990) 110
Rodbell, K.P., see Guo, X.S. ... B45 (1990) 123
Rodbell, K.P., see Guo, X.S. ... B45 (1990) 157
Rolfe, S., see Jackman, J.A. ... B45 (1990) 592
Ross, G.G. and B. Terreault, ERD measurement of the mean ranges and variances of 0.75–2.0 keV deuterium ions in Be, C and Si ... B45 (1990) 190
Rossman, G.R., Hydrogen in "anhydrous" minerals ... B45 (1990) 41
Rossouw, C.J., see Wielunski, L.S. ... B45 (1990) 455
Rossouw, C.J., see Wielunski, L.S. ... B45 (1990) 459
Rubenstein, D., see Williams, E.T. ... B45 (1990) 356
Rucklidge, J.C., G.C. Wilson and L.R. Kilius, AMS advances in the geosciences and heavy-element analysis ... B45 (1990) 565
Ryan, C.G., see Sie, S.H. ... B45 (1990) 543
Ryan, C.G., see Sie, S.H. ... B45 (1990) 604
Rydén, J., see Hjörvarsson, B. ... B45 (1990) 36
Ryerson, F.J., see Cherniak, D.J. ... B45 (1990) 230

Sakairi, H., see Kobayashi, T. ... B45 (1990) 208
Sakairi, H., see Kobayashi, T. ... B45 (1990) 480
Salomon, J., see Amsel, G. ... B45 (1990) 296
Salomon, J., see Menu, M. ... B45 (1990) 610
Sandhu, G.S., see Liu, B. ... B45 (1990) 420
Sanz-Garcia, J.A., see Rebouta, L. ... B45 (1990) 495
Satou, M., see Kinomura, A. ... B45 (1990) 523
Satou, M., see Kinomura, A. ... B45 (1990) 536
Savin, W. and L.C. Feldman, Depth-dependent defect analysis in RBS/channeling ... B45 (1990) 417
Scanlon, P.J., M.C. Ridgway and H.H. Brongersma, Detection of surface accumulation of dopants in rapid-thermally-annealed, shallow-implant silicon ... B45 (1990) 615
Schempp, A., RFQ ion acclerators ... B45 (1990) 302
Scherzer, B.M.U., J. Wang and W. Möller, Dynamic inventory of implanted deuterium in graphite at 116–223 K ... B45 (1990) 54
Scherzer, B.M.U., Hydrogen in the first wall of nuclear fusion plasma devices ... B45 (1990) 57
Schidlovsky, G., see Gordon, B.M. ... B45 (1990) 527
Schillaci, M.E., see Dicello, J.F. ... B45 (1990) 135
Scholberg, K., see Houdayer, A.J. ... B45 (1990) 632
Schreiner, W.H., see Stedile, F.C. ... B45 (1990) 627
Schüle, V., see Oberschachtsiek, P. ... B45 (1990) 20
Seiberling, L.E., see Reid, I. ... B45 (1990) 347
Shaanan, M., see Smulders, P.J.M. ... B45 (1990) 450
Shigematsu, K., see Kobayashi, T. ... B45 (1990) 480
Shoji, F., see Oura, K. ... B45 (1990) 199
Shoji, F., see Nakahara, T. ... B45 (1990) 467
Sie, S.H., C.G. Ryan, D.R. Cousens and G.F. Suter, A Tandetron-based microbeam system ... B45 (1990) 543
Sie, S.H., C.G. Ryan, D.R. Cousons and W.L. Griffin, IBA in minerals research: progress and prospects ... B45 (1990) 604
Siejka, J., see Abel, F. ... B45 (1990) 100
Siejka, J., see Ortega, C. ... B45 (1990) 622
Singer, M.A., see Palmer, G.R. ... B45 (1990) 337
Sisterson, J.M., Overview of proton beam applications in therapy ... B45 (1990) 718
Smith, G.A., see Luo, L. ... B45 (1990) 488

Smith, G.R., see McKee, J.S.C. B45 (1990) 513
Smith, R.J., A.W. Denier van der Gon and J.F. Van der Veen, Peak shape analysis for the determination of interface structure in reactive metallic bilayers: Pd on Al B45 (1990) 429
Smulders, P.J.M., D.O. Boerma, B. Bech Nielsen and M.L. Swanson, Lattice site location of clustered boron atoms in silicon B45 (1990) 438
Smulders, P.J.M., D.O. Boerma and M. Shaanan, Lattice site location of Te in GaAs B45 (1990) 450
Soares, J.C., see Rebouta, L. B45 (1990) 495
Soejima, H., see Katayama, M. B45 (1990) 408
Sofield, C.J., Heavy-ion energy loss B45 (1990) 684
Sorensen, G., see Terwagne, G. B45 (1990) 95
Souda, R., T. Aizawa, C. Oshima and Y. Ishizawa, Electronic excitation and charge exchange in low-energy He^+ scattering from solid surfaces B45 (1990) 364
Souda, R., T. Aizawa, C. Oshima and Y. Ishizawa, Inelastic scattering of D, He, and Li ions from KI B45 (1990) 369
Spanne, P., see Gordon, B.M. B45 (1990) 527
Spinella, C., see Calcagno, L. B45 (1990) 442
Stalder, C., see Neumann, W. B45 (1990) 126
Stanley, C.J., see Reeson, K.J. B45 (1990) 327
Stedile, F.C., D.H. Mosca Jr, C.V. Barros Leite, F.L. Freire Jr, W.H. Schreiner and I.J.R. Baumvol, The analysis of semiconductor thin films with complementary Mössbauer scattering–RBS, channeling and nuclear reaction B45 (1990) 627
Steinbauer, E., P. Bauer and J. Biersack, Monte Carlo simulation of RBS spectra: comparison to experimental and empirical results B45 (1990) 171
Stern, M., see El Bouanani, M. B45 (1990) 651
Storey, R.S., see Jackman, J.A. B45 (1990) 592
Suter, G.F., see Sie, S.H. B45 (1990) 543
Sutton, S.R., see Gordon, B.M. B45 (1990) 527
Swann, C.P., P.E. McGovern and S.J. Fleming, Colorants used in ancient Egyptian glassmaking: specialized studies using PIXE spectrometry B45 (1990) 311
Swanson, M.L., see Parkih, N.R. B45 (1990) 70
Swanson, M.L., see Hofsäss, H.C. B45 (1990) 151
Swanson, M.L., see Liu, B. B45 (1990) 420
Swanson, M.L., see Smulders, P.J.M. B45 (1990) 438
Swietlicki, E., see Lövestam, N.E.G. B45 (1990) 307

Takagi, K., see Agawa, Y. B45 (1990) 540
Takahara, H., see Kobayashi, T. B45 (1990) 480
Takahari, T., see Tanaka, K. B45 (1990) 471
Takahashi, K., see Fujihana, T. B45 (1990) 669
Takahashi, T., see Kobayashi, T. B45 (1990) 480
Takai, M., see Kinomura, A. B45 (1990) 523
Takai, M., see Kinomura, A. B45 (1990) 536
Takai, M., see Agawa, Y. B45 (1990) 540
Takai, M., T. Matsuo, A. Kinomura, S. Namba, K. Inoue, K. Ishibashi and Y. Kawata, A microbeam line for medium-energy ion beams B45 (1990) 553
Takekawa, S., see Kobayashi, T. B45 (1990) 480
Tanaka, K., E. Yagi, N. Masahashi, Y. Mizuhara, K. Tatsumi and T. Takahari, Lattice location of B atoms in $Ni_{0.75}Al_{0.15}Ti_{0.10}$ intermetallic compounds as observed by the channeling method B45 (1990) 471
Tanaka, M., Y. Iwata, F. Fujimoto, K. Komaki, K. Kobayashi, H. Yamashita and M. Haba, Determination of the infrared proportionality coefficient of the CH_n stretching mode for a-C:H and a-SiC:H films using ERD methods B45 (1990) 223
Tao, K., see Zhang, J. B45 (1990) 239
Tapper, U.A.S., see Pallon, J. B45 (1990) 548
Tatsumi, K., see Tanaka, K. B45 (1990) 471
Terreault, B., see Ross, G.G. B45 (1990) 190
Terwagne, G., S. Lucas, F. Bodart, G. Sorensen and H. Jensen, Study of ionic movements during anodic oxidation of nitrogen-implanted aluminium B45 (1990) 95
Tesmer, J.R. and M. Nastasi, Oxygen depth-profile channeling of radiation-damaged high-T_c thin-film superconductors B45 (1990) 476
Themner, K., see Pallon, J. B45 (1990) 548
Thomas, J.P., see Fallavier, M. B45 (1990) 130
Tirira, J., P. Trocellier and J.P. Frontier, Analytical capabilities of ERDA in transmission geometry B45 (1990) 147

Tirira, J., P. Trocellier, J.P. Frontier and P. Trouslard, Theoretical and experimental study of low-energy ^{4}He-induced ^{1}H elastic recoil with application to hydrogen behavior in solids B45 (1990) 203
Tong, S.Y., W.N. Lennard, P.F.A. Alkemade and I.V. Mitchell, Behaviour of the ^{12}C(^{4}He, ^{4}He)^{12}C elastic scattering cross section at $E_{\alpha} = 0.4$–1.8 MeV B45 (1990) 30
Tong, S.Y., W.N. Lennard, P.F.A. Alkemade and I.V. Mitchell, Absolute surface carbon coverage determination via the ^{12}C(^{3}He, p)^{14}N reaction B45 (1990) 91
Tong, S.Y., see Mitchell, I.V. B45 (1990) 107
Tong, S.Y., see Lennard, W.N. B45 (1990) 281
Tousset, J., see Moncoffre, N. B45 (1990) 81
Tregoat, Y., see Barthe, M.F. B45 (1990) 105
Trocellier, P., see Tirira, J. B45 (1990) 147
Trocellier, P., see Tirira, J. B45 (1990) 203
Trouslard, P., see Tirira, J. B45 (1990) 203
Tsartsarakos, C., P. Misaelides and A. Katsanos, Cross sections for the ^{32}S(p, p'γ)^{32}S nuclear reaction used for the profiling of sulphur on materials surfaces B45 (1990) 33
Tsong, I.S.T., see Cornelison, D.M. B45 (1990) 394
Tsuboi, H., see Agawa, Y. B45 (1990) 540

Uchiyama, T., see Agawa, Y. B45 (1990) 540
Umezawa, K., see Oura, K. B45 (1990) 199

Van der Veen, J.F., see Deckers, S. B45 (1990) 416
Van der Veen, J.F., see Smith, R.J. B45 (1990) 429
Van der Weg, W.F., see Alkemade, P.F.A. B45 (1990) 139
Van der Weg, W.F., see Deckers, S. B45 (1990) 416
Van der Zwan, L., see Jackman, J.A. B45 (1990) 592
Van Leerdam, G.C., K.-M.H. Lenssen and H.H. Brongersma, Charge exchange processes in low-energy He^{+} ion scattering from Si and Pd_2Si surfaces B45 (1990) 390
Van Rinsvelt, H.A., see Reid, I. B45 (1990) 347
Vanacken, J., see Wu, M.F. B45 (1990) 658
Vandervorst, W., see Mertens, P.W. B45 (1990) 586
Vanhellemont, J., see Wu, M.F. B45 (1990) 658
Vantomme, A., see Wu, M.F. B45 (1990) 658
Verhey, L.J., see Dicello, J.F. B45 (1990) 724
Viargues, F., see Daudin, B. B45 (1990) 290
Vickridge, I. and G. Amsel, SPACES: a PC implementation to the stochastic theory of energy loss for narrow-resonance depth profiling B45 (1990) 6
Vickridge, I., see Amsel, G. B45 (1990) 12
Vickridge, I. and G. Amsel, Calculation of energy loss spectra through very thin layers: application to tandem accelerator gas strippers B45 (1990) 16
Vickridge, I.C., see Walter, P. B45 (1990) 119
Vizkelethy, G., Simulation and evaluation of nuclear reaction spectra B45 (1990) 1
Vizkelethy, G., see Abel, F. B45 (1990) 100
Vizkelethy, G., see Ortega, C. B45 (1990) 622
Vloeberghs, H., see Wu, M.F. B45 (1990) 658

Walsh, D.S., J.M. Knox and B.L. Doyle, External ion beam analysis of the TFTR bumper limiters B45 (1990) 62
Walsh, D.S., see Lee, S.R. B45 (1990) 285
Walter, P., M. Menu and I.C. Vickridge, Fluorine depth profiles as a relative dating method of chipped flints .. B45 (1990) 119
Wang, J., see Scherzer, B.M.U. B45 (1990) 54
Watt, F., see Reeson, K.J. B45 (1990) 327
Watt, F., see Grime, G.W. B45 (1990) 508
Watterson, J.I.W., A.E. Pillay and P. Nailand, Selective activation analysis with ion-beam-tailored neutron spectra – A comparison between the reactions ^{7}Li(p, n)^{7}Be and ^{9}Be(p, n)^{9}B B45 (1990) 75
Weiser, M., see Oberschachtsiek, P. B45 (1990) 20
Wesch, W., K. Gärtner, A. Jordanov and G. Götz, Investigation of defects in GaAs by dechanneling B45 (1990) 446
Wielunski, L.S., M.S. Kwietniak, G.N. Pain and C.J. Rossouw, Structural analysis of an epitaxial layer of CdTe on GaAs by the multidirectional channeling technique B45 (1990) 455
Wielunski, L.S., M.S. Kwietniak, G.N. Pain and C.J. Rossouw, Polarity determination of epitaxial structures of CdTe on GaAs by channeling techniques B45 (1990) 459
Willemsen, M.F.C. and A.E.T. Kuiper, LPCVD of tungsten studied with in-situ RBS B45 (1990) 242

Williams, E.T., X. Wu, R. Alkins, R. Craig, C. Davis, I. Gaskin and D. Rubenstein, PIXE: a tool for research and education . . . B45 (1990) 356
Williams, R.S., see Daley, R.S. . . . B45 (1990) 380
Wilson, G.C., see Rucklidge, J.C. . . . B45 (1990) 565
Wittmaack, K., see Menzel, N. . . . B45 (1990) 219
Wolf, G.K., see Laursen, T. . . . B45 (1990) 66
Wong, L., see Lennard, W.N. . . . B45 (1990) 281
Wong, L., P.F.A. Alkemade, W.N. Lennard and I.V. Mitchell, Ion-induced Auger electron studies on Al(110) . . B45 (1990) 637
Wu, M.F., A. Vantomme, H. Pattyn, G. Langouche, K. Maex, J. Vanhellemont, J. Vanacken, H. Vloeberghs and Y. Bruynseraede, Formation of buried and surface $CoSi_2$ layers by ion implantation . . . B45 (1990) 658
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Wu, X., see Williams, E.T. . . . B45 (1990) 356
Wulf, F., see Briere, M.A. . . . B45 (1990) 45

Xi, X.X., see Meyer, O. . . . B45 (1990) 483
Xiao, Q.F., see Hashimoto, S. . . . B45 (1990) 434
Xiao, Q.F., S. Hashimoto, W.M. Gibson and S.J. Pearton, Channeling lattice location of Se implanted into InP by RBS and PIXE . . . B45 (1990) 464
Xu Hong-Jie, see Cheng Huan-Sheng . . . B45 (1990) 424

Yabe, K., see Iwaki, M. . . . B45 (1990) 212
Yagi, E., see Tanaka, K. . . . B45 (1990) 471
Yamakawa, H., see Agawa, Y. . . . B45 (1990) 540
Yamamoto, Y., see Hamanaka, H. . . . B45 (1990) 360
Yamamura, Y., N. Matsunami and K. Kitoh, A computer study of the energy loss spectrum of 100 keV H^+ at a W(111) surface . . . B45 (1990) 403
Yamamura, Y., Time-dependent angular distribution of sputtered particles from amorphous targets . . . B45 (1990) 582
Yamamura, Y., Computer simulation of ionized cluster beam bombardment on a carbon substrate . . . B45 (1990) 707
Yamane, J., see Oura, K. . . . B45 (1990) 199
Yamashita, H., see Tanaka, M. . . . B45 (1990) 223
Yan, X., see Zhang, J. . . . B45 (1990) 239
Yang Fu-Jia, see Cheng Huan-Sheng . . . B45 (1990) 424
Yang Fujia, see Wu Shiming . . . B45 (1990) 227
Yao Xiao-Wei, see Cheng Huan-Sheng . . . B45 (1990) 424
Yao Xiaowei, see Wu Shiming . . . B45 (1990) 227
Yeo, Y.H., see McKee, J.S.C. . . . B45 (1990) 513

Zabel, T.H., see Chou, N.J. . . . B45 (1990) 86
Zawislak, F.C., see Grande, P.L. . . . B45 (1990) 689
Zhang, J., K. Tao and X. Yan, Investigation of a molybdena crystal by RBS . . . B45 (1990) 239
Zhang Chengteng, see Wu Shiming . . . B45 (1990) 227
Zhao Guoqing, see Wu Shiming . . . B45 (1990) 227
Zironi, E.P., J. Rickards, A. Maldonado and R. Asomoza, A study of fluorine in tin oxide films . . . B45 (1990) 115